Wentworth Laboratories

www.wentworthlabs.com



PROBE CARDS CANTILEVER BLADE & EPOXY TECHNOLOGY

Multi-DUT Analog, Logic & Memory solutions. Fine Pitch available with inline pitch capability as low as 25um, and staggered pitch of 12/24um. High Temperature probe cards up to 400oC, all provided via our complete turn key service.

Leader In **P**robe**A**bility

ADVANCED CANTILEVER PROBE CARDS

WITH PAD SIZES CONTINUING TO SHRINK ALIGNMENT AND PLANARITY ACCURACY BECOMES EXTREMELY IMPORTANT. WENTWORTHS UNIQUE MANUFACTURING PROCESSES AND METROLOGY EQUIPMENT ALLOWS FOR EXCEPTIONAL POSITIONAL ACCURACY AND EXTENDED LIFETIMES.

FINE PITCH

Utilizing the latest Cantilever design and manufacturing techniques Wentworth can offer Multi-DUT fine pitch probe cards with in-line pitch capability as low as 25um, and staggered pitches of 12/24um.

With pad sizes continuing to shrink alignment and planarity accuracy becomes extremely important. Wentworth's unique manufacturing processes and metrology equipment allows for exceptional positional and planarity accuracy and also extended lifetimes.



MULTI-DIE

Multi-DUT analog and logic cards available in x1, x2, diagonal, or 2x2 (shelf) arrays with a minimum inline pitch capability as low as 30um



HIGH TEMPERATURE

Wentworth's high temperature probe cards have been developed for long term reliability and characterization at both low and high temperatures

High Temperature PCB materials, ceramics and heat shield reduce the thermal effects on both the probe card and the prober. Allowing Wentworth probe cards to be used in the harshest of environments

HIGH VOLTAGE/HIGH CURRENT

High Current probe cards (up to 100A) handle and distribute excessive current loads. Dedicated HV/HC probe cards solutions reduce probe and device destruction at high voltages/currents to prevent device heating/arcing at the tip.

LOW LEAKAGE

Wentworth's low leakage parametric probe cards deliver ultra low leakage measurements, wide operating temperature range with ultra high performance.

Low Leakage probe cards are assembled, cleaned and tested to tightly controlled specifications Leakage testing, using Keithley & Agilent programmable electrometers, to verify the card's continuity and leakage characteristics.

Customers are assured that critical parametric measurements necessary for superior wafer test yield are obtainable with Wentworth Low Leakage probe card designs.



MATCHED IMPEDANCE

Short Beam Length and small ring designs allow for match impedance and reduced probe length, allow testing between 500-800 mHz without using more expensive less flexible solutions

Wentwo	orth ries CANTILEVER APPLIC/	Wentwo Laboratori	rth ies CANTILEV	ER APPLICATION DATA FORM
1: Confirm Contact Details 2: Order Information 3: Device Information 4: Tester Information 5: Metrology Details 6: Probe Assembly 7: PCB Details 9: XY Trace (NET List) 10: Notes 11: SUMMARY Probe Card Illustration	Number of DUTs: DUT Layout: Step Size: X Pdds / DUT: Total number of Probes:	2. Order Information 3. Device Information 4. Tester Information 5. Netrology Details 6. Probe Assembly 7. PCB Details 8. Edge Sensor Details 9. XY Trace (NET List) 10. Notes 11. SUMMARY Probe Card Illustration Customer Revision History	PCB Type: Part Number: PCB Geometry :	
Customer Revision History	Die Size: X: Y: [Minimum Pad Size: X: Y: [Minimum Pad Pitch:] µm Pad Material: Other:] Pad Type:] High Current Application? [Low Leakage Application?] High Frequency Application?]		PCB Orientation : PCB Marker : PCB Marker : PCB Material : PCB Keep Out : Mounting Rings : Stiffener : Terminal Pins : Connector Quantity: Connector Duppler : Connector Partie	in

Solar™



Database Software Suite

KEY FOR DESIGN SUCCESS

Wentworth's Solar[™] Cantilever Probe Card Design and Database Software Suite assures quality and facilitates communication.

- Supports the automated design of key components such as rings and fixtures.
- Imports all device specific data automatically creating all manufacturing documentation.
- Facilitates the automatic programming of key manufacturing equipment and tracks progress through each manufacturing process.
- Controls state-of-the-art in-situ micro machining tools.

Wentworth offers a comprehensive library of master templates for all major tester platforms, utilizing advanced design software for quick-turn printed circuit boards (PCBs).

Sophisticated mechanical design modeling software speeds up the custom design of complex cantilever probe cards. In addition, our turnkey service includes the custom design of interfaces from the probe card to the tester.

LOW COST OF OWNERSHIP

- Excellent longevity after 1M Touchdowns.
- ✓ Tip Wear Tip diameter delta < 1 micron</p>
- Alignment Delta < ± 6 micron for slide
 Delta < ± 5 micron for horizontal
- Planarity Delta 5 micron
- CRes Delta .25 ohms (100 micron OD)

CUSTOM PCB DESIGN

Cadence Orcad PCB Designer software and process: ISO 9001 compliant IPC Standards.

- Customized Internal Checklists
- Design Time < 3 weeks





C .	CANTILEVER PROBE CARD SPECIFICATIONS																							
		PROBE QTY			PROBE MAT			PCB MAT		TEMP			PITCH			LEAKAGE			CURRENT					
		1-48 (Generic)	49 - 70 (Generic)	71 - 128 (Generic)	129 + (Generic)	Tungsten (W)	Rhenium Tungsten (ReW)	Beryllium Copper (BeCu)	Pallaidium (Pd)	FR4	HTG-FR4	Polyimide	Ambient > +100oC	Ambient > +180oC	-40oC > +250oC	25um - 45um Staggered *	45um -61um	60um +	nA	pA	fA	up to 100mA	up to 700mA	700mA to 150A (Pulsed)
TECHNOLOGY	Standard Epoxy	~	~	~	~	~	~	~	>	~	~		~	>		 Image: A start of the start of	>	>	>	>		>	~	
	High Temperature Epoxy	>	~	>	~	~	>					~	~	~	>		~	~	~	<		~	>	
	High Current (kV Probing)	~	~	~	~	~	~	~	>			~	~					>	>			>	~	~
	Low Leakage Epoxy	~				~	~	~	-	~	~	>	~			~	>	>		<	>	>		
	Short Beam/Shielded Epoxy	~	~	~	~	~	~	~	~	~	~	~	~			~	~	~	~	>				
	DSP Epoxy	~				~	~	~	~				~				~	~	~	>		~		
	Standard Blade	~	~			~	~	~	<	~			~					>	>	>		>		
	ACS Stripline Blade	~				~	~	~	✓	~	~	~	~					~			~	~		

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